

Notice of References Cited	Application/Control No. 10/810,602	Applicant(s)/Patent Under Reexamination YEH, CHI-YEE	
	Examiner Mark Halpern	Art Unit 1731	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0045690	03-2004	Eto et al.	162/225
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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